

**Texas Instruments Incorporated**

P st Office Box 655474, MS 3999
Dallas, Texas 75265-5474
7839 Churchill Way
Dallas, Texas 75251-1900

(972) 917-5557

FAX COVER SHEET

Page 1 of 5

DATE:

12/20/99

FROM:

David Denker

COMPANY:

Texas Instruments Incorporated

PHONE NUMBER: (972) 917-4888

FAX NUMBER: (972) 917-4418

TO:

Examiner: B. Su

U.S. Patent & Trademark Office

Group: 2814

PHONE NUMBER: 703- 305-1481

FAX NUMBER: 703- 308-7722

Re: Appl. #: 09/116,138

Atty Docket: TI-24953

Rule 111 Reply

EOT, 1 month

FAX COPY RECEIVED
DEC 20 1999
TECHNOLOGY CENTER 2800

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the application of: Anthony *et al.*

Docket: TI-24953

Serial No.: 09/116,138

Examiner: B. Su

Filed: 07/15/98

Art Unit: 2814

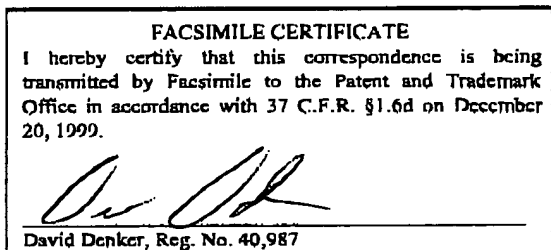
For: High Permittivity Silicate Gate Dielectric

REPLY PURSUANT TO 37 C.F.R. § 1.111

November 18, 1999

Ass't Commissioner for Patents
Washington, DC 20231

Examiner:



Please amend the above-identified patent application as follows:

IN THE SPECIFICATION:

Page 1, lines 8 and 9, Please change "Serial No. TBD (TI-25859) and Serial No. TBD (TI-26146)" to --Serial No. 09/115,855 and Serial No. 09/115,856 --.

Page 14, between lines 4 and 5, Please add a new paragraph.

Several metal silicates that address these preferences are zirconium silicate, cerium silicate, zinc silicate, thorium silicate, bismuth silicate, hafnium silicate, lanthanum silicate, tantalum silicate, and combinations thereof. The examples below will focus on zirconium silicate and hafnium silicate.

IN THE CLAIMS:

Please cancel Claims 31 - 35.

Please amend Claim 25.

FAX COPY RECEIVED
DEC 20 1999
TECHNOLOGY CENTER 2800